

FYS4310

Bipolar Process Integration



Pavement university of Aveiro, Portugal

Outline

Simple

More advanced

Overview and some details

“Curriculum-reading list”

Understand how bipolar works, Understand design philosophy

17.6 not 17.7 (Review of Bipolar Devices [not Performance of BJT])

17.8, 17.9 not 17.10(Early Bipolar Process, Advanced, not BiCMOS)

(17.11 FET), 17.12 (Summary_

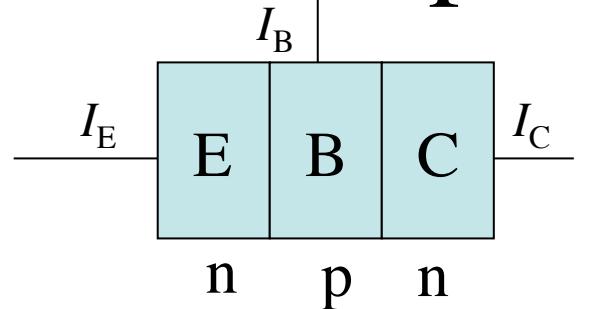
All lecture

Know about/understand interaction between processes

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Bipolar Process Integration

Bipolar parameters



$$I_C = \alpha I_E$$

$$I_C = \beta I_B$$

$$I_E = I_C + I_B$$

$$\beta = \alpha / (1 - \alpha)$$

$$\alpha = \beta / (\beta + 1)$$

$$I_C = \alpha_T \gamma \delta I_E$$

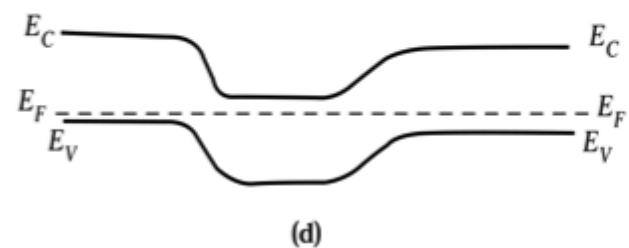
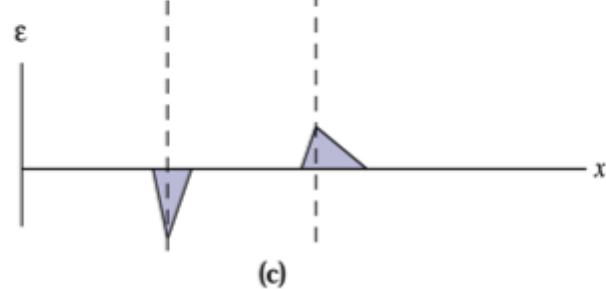
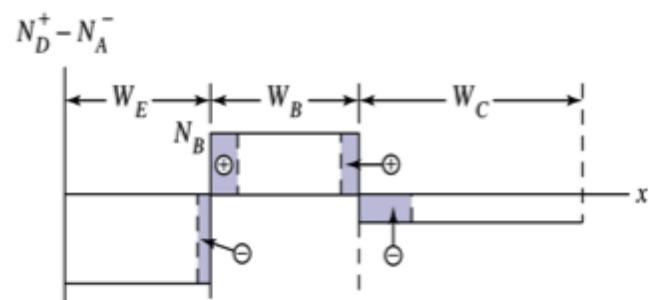
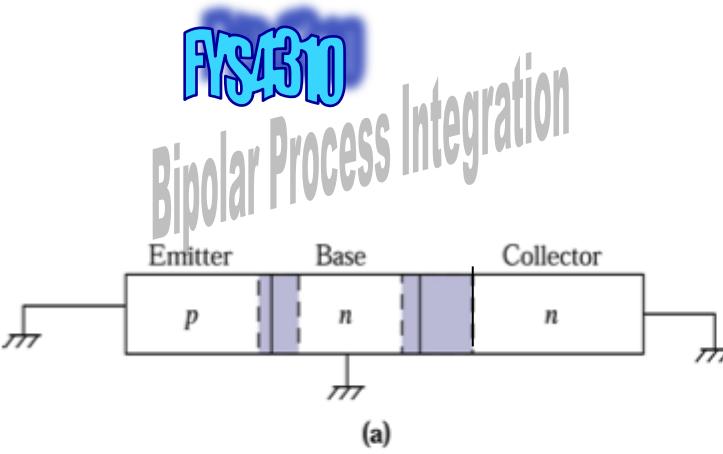
α_T :Base transport factor

α : common base current gain

γ :Emitter injection efficiency

β : common emitter current gain

δ :Recombination factor



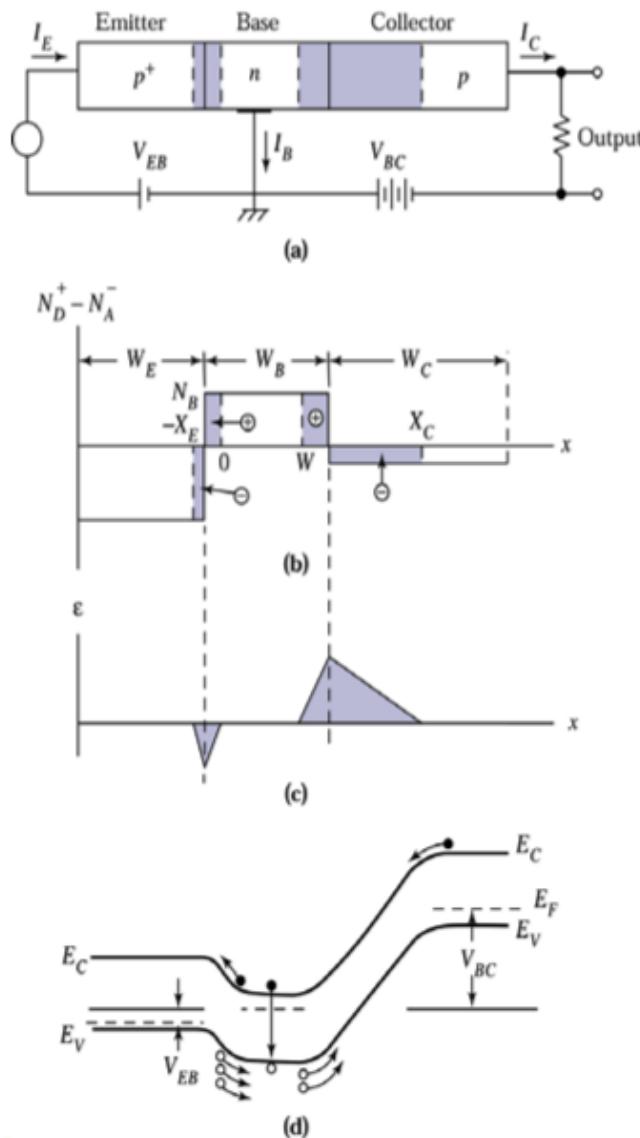
Bipolar Quick repetition

Bipolar Transistor (no bias)

(a) A *p-n-p* transistor with all leads grounded (at thermal equilibrium). (b) Doping profile of a transistor with abrupt impurity distributions. (c) Electric-field profile. (d) Energy band diagram at thermal equilibrium.

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Bipolar Process Integration



Bipolar Quick repetition

Bipolar Transistor
Active mode operation under bias

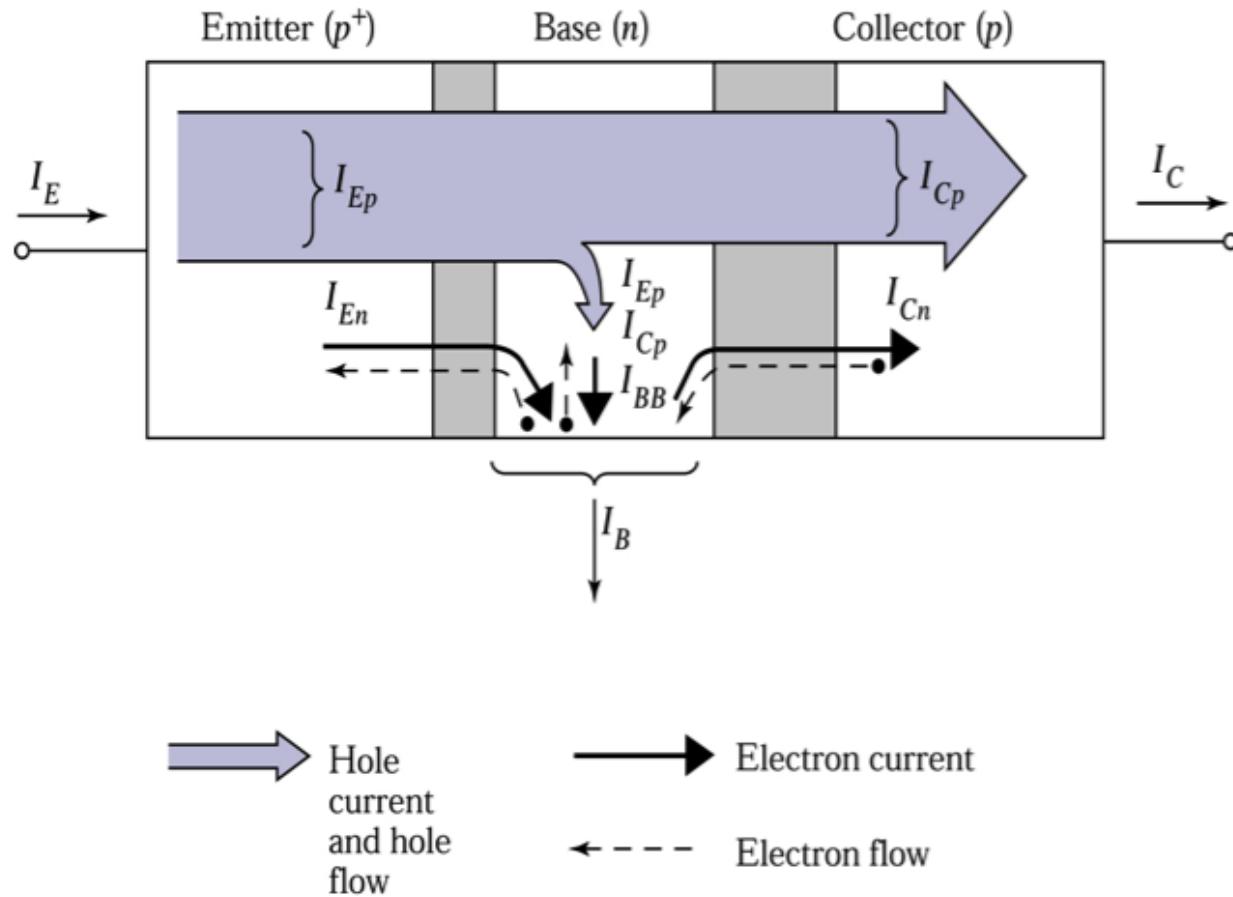
- (a) The transistor is shown in this Figure under the active mode of operation.
- (b) Doping profiles and the depletion regions under biasing conditions. (c) Electric-field profile. (d) Energy band diagram.



Bipolar Quick repetition

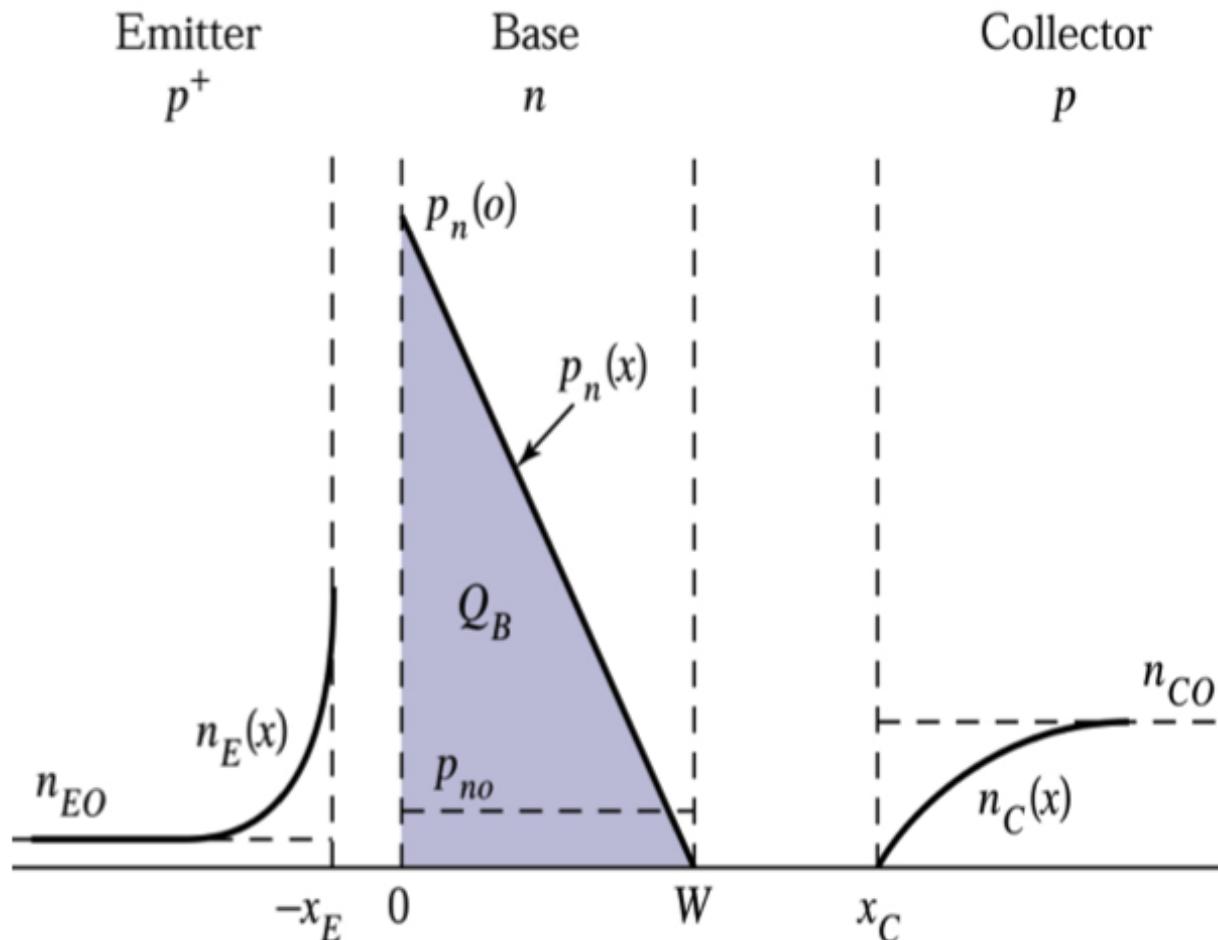
Bipolar Transistor

Current gain



Various current components in a *p-n-p* transistor under active mode of operation. The electron flow is in the opposite direction to the electron current.

Carrier Distribution in Each Region

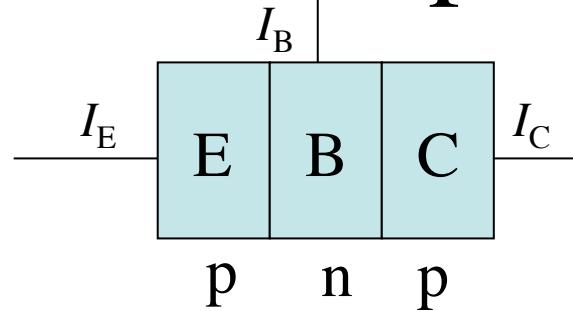


Minority carrier distribution in various regions of a *p-n-p* transistor under the active mode of operation.

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Bipolar Process Integration

Bipolar parameters



$$I_C = \alpha I_E$$

$$I_E = I_C + I_B$$

$$I_C = \beta I_B$$

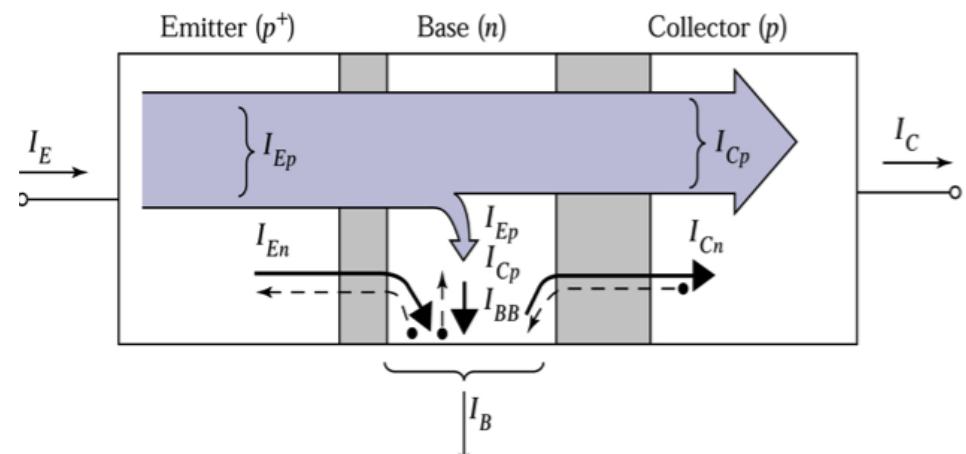
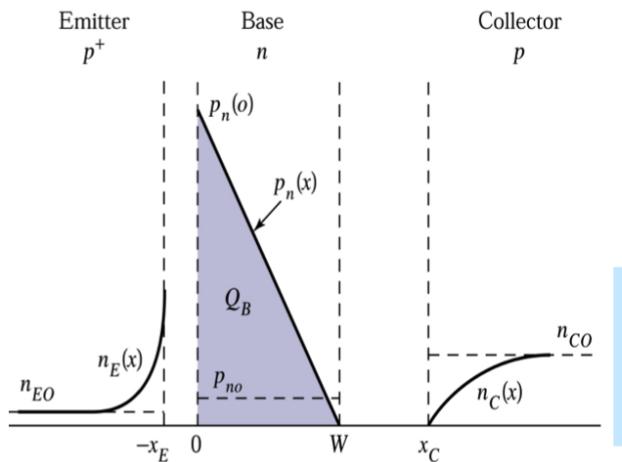
$$\beta = \alpha / (1 - \alpha)$$

α_T :Base transport factor

$$I_C = \alpha_T \gamma \delta I_E$$

γ :Emitter injection efficiency

δ :Recombination factor

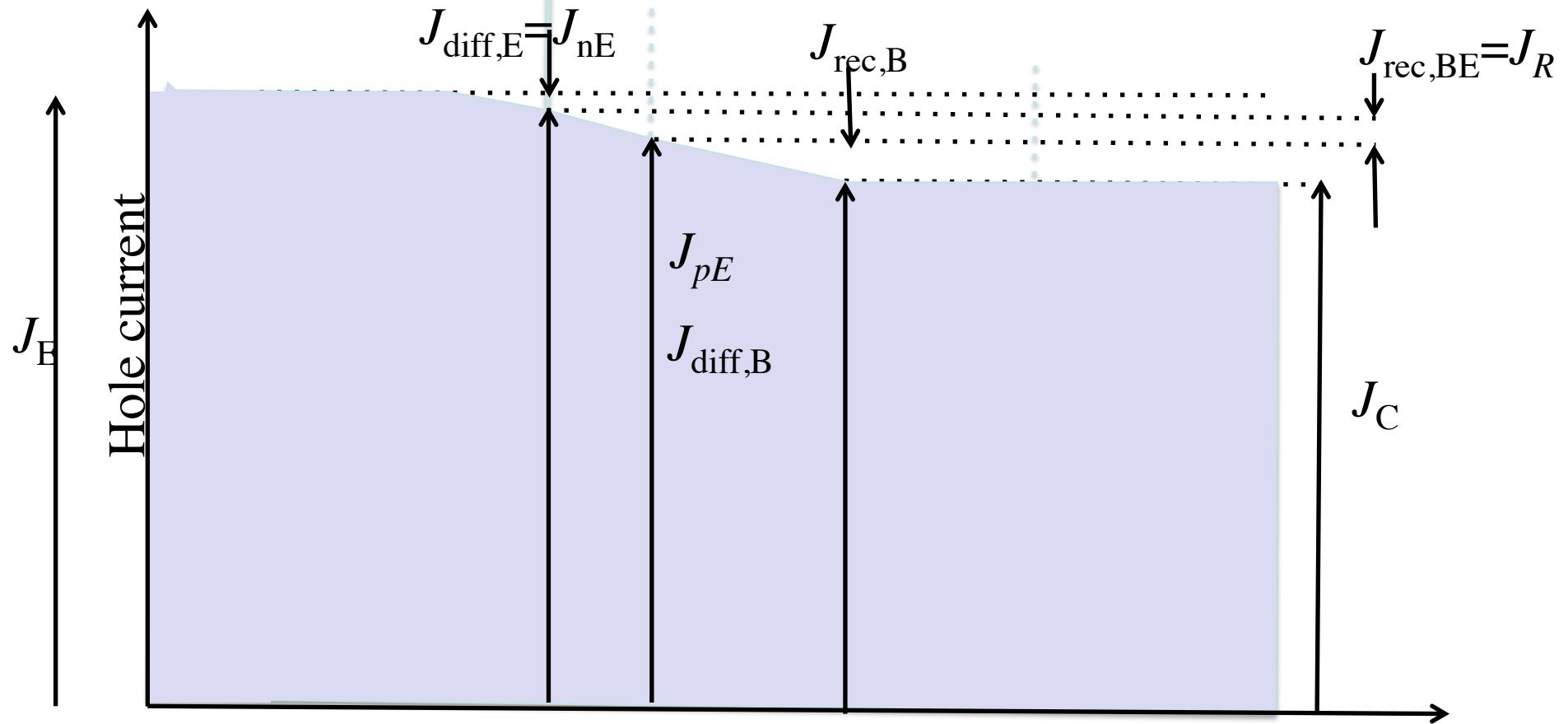


FSI310

Bipolar Process Integration

$$\text{DC } \alpha_0 = \frac{J_C}{J_E} = \frac{J_{pC} + J_G + J_{nC0}}{J_{pE} + J_E + J_{nE}}$$

$$\text{AC } \alpha = \frac{\partial J_C}{\partial J_E} = \frac{J_{pC}}{J_{pE} + J_R + J_{nE}} = \left(\frac{J_{pE}}{J_{pE} + J_{nE}} \right) \left(\frac{J_{pC}}{J_{pE}} \right) \left(\frac{J_{pE} + J_{nE}}{J_{pE} + J_{nE} + J_R} \right)$$

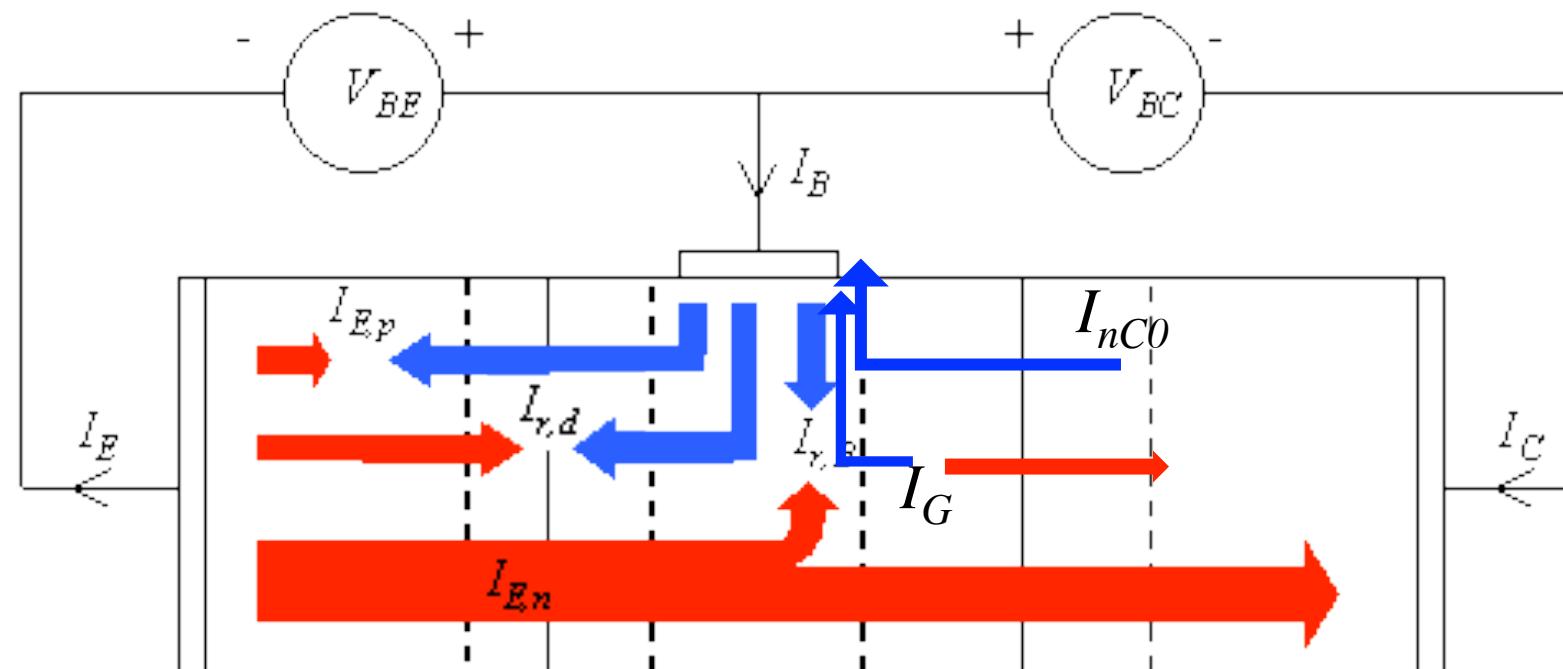


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Bipolar Process Integration

$$\text{DC } \alpha_0 = \frac{J_C}{J_E} = \frac{J_{pC} + J_G + J_{nC0}}{J_{pE} + J_E + J_{nE}}$$

$$\text{AC } \alpha_0 = \frac{\partial J_C}{\partial J_E} = \frac{J_{pC}}{J_{pE} + J_R + J_{nE}} = \left(\frac{J_{pE}}{J_{pE} + J_{nE}} \right) \left(\frac{J_{pC}}{J_{pE}} \right) \left(\frac{J_{pE} + J_{nE}}{J_{pE} + J_{nE} + J_R} \right)$$



n

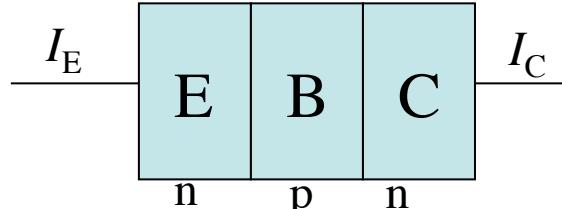
p

n

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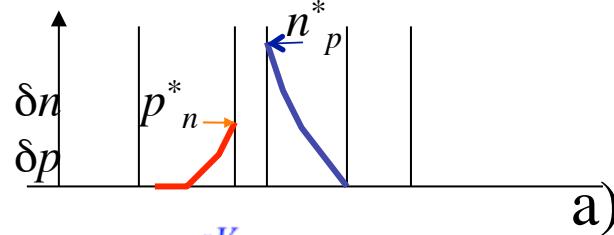
Bipolar Process Integration

Emitter injection efficiency : γ



$$I_C = \alpha_T \gamma \delta I_E$$

$$\gamma = \frac{J_{nE}}{J_{pE} + J_{nE}}$$



$$J_{nE} = -D_{nB} \frac{\partial}{\partial x} n_p \Big|_{x=0} = -D_{nB} \frac{n_{p0} e^{-\frac{qV_{BE}}{kT}}}{W_B}$$

b)

$$J_{pE} = \frac{D_{pE} p_{n0} e^{-\frac{qV_{BE}}{kT}}}{L_{pE}}$$

$$\gamma = \frac{D_{nB} n_{p0} e^{-\frac{qV_{BE}}{kT}}}{W_B \left(\frac{D_{nB} n_{p0} e^{-\frac{qV_{BE}}{kT}}}{W_B} + \frac{D_{pE} p_{n0} e^{-\frac{qV_{BE}}{kT}}}{L_{pE}} \right)} = \frac{1}{\frac{D_{pE} N_{AB} W_B}{D_{nB} L_{pE} N_{DE}} + 1}$$

$$\gamma = 1$$

$$n_p^* \gg p_n^*$$

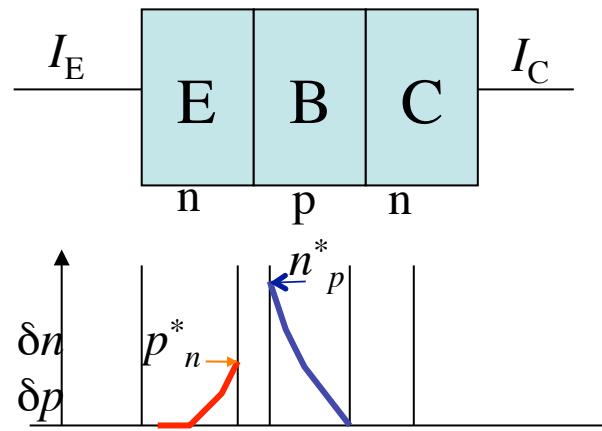
$$N_E \gg N_B$$

$$W_E \gg W_B$$

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Bipolar Process Integration

Emitter injection efficiency : γ



$$\gamma = 1$$

$$n_p^* \gg p_n^*$$

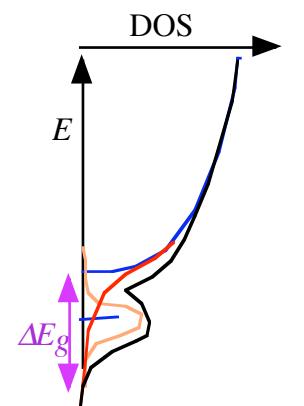
$$N_E \gg N_B$$

$$W_E \gg W_B$$

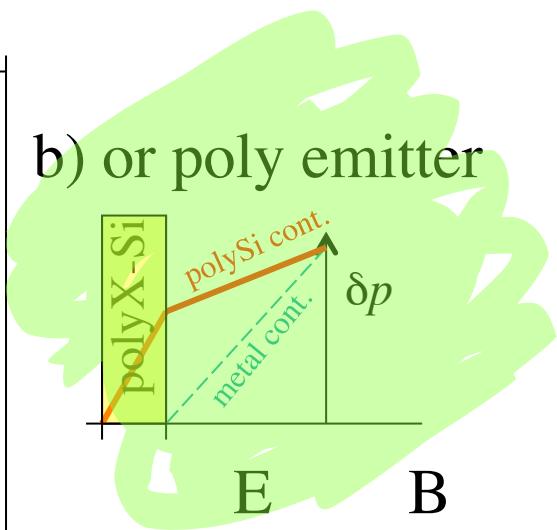
$$I_C = \alpha_T \gamma \delta I_E$$

a)

b)



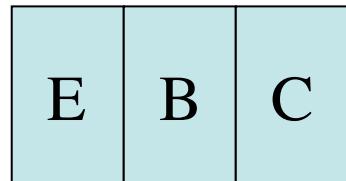
a) For very high emitter doping
Band gap smaller, γ decreases
Heterojunction bipolar, E(Si), B(SiGe)



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Bipolar Process Integration

Base transport factor : α_T



$$\alpha_T = 1$$

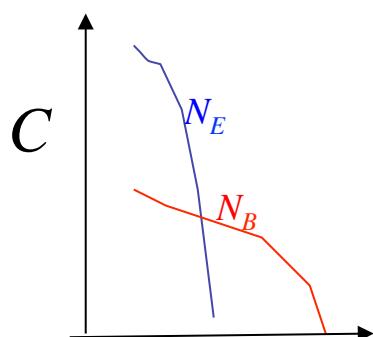
W_B minimize

$$I_C = \alpha_T \gamma \delta I_E$$

Limit: punch through, precision

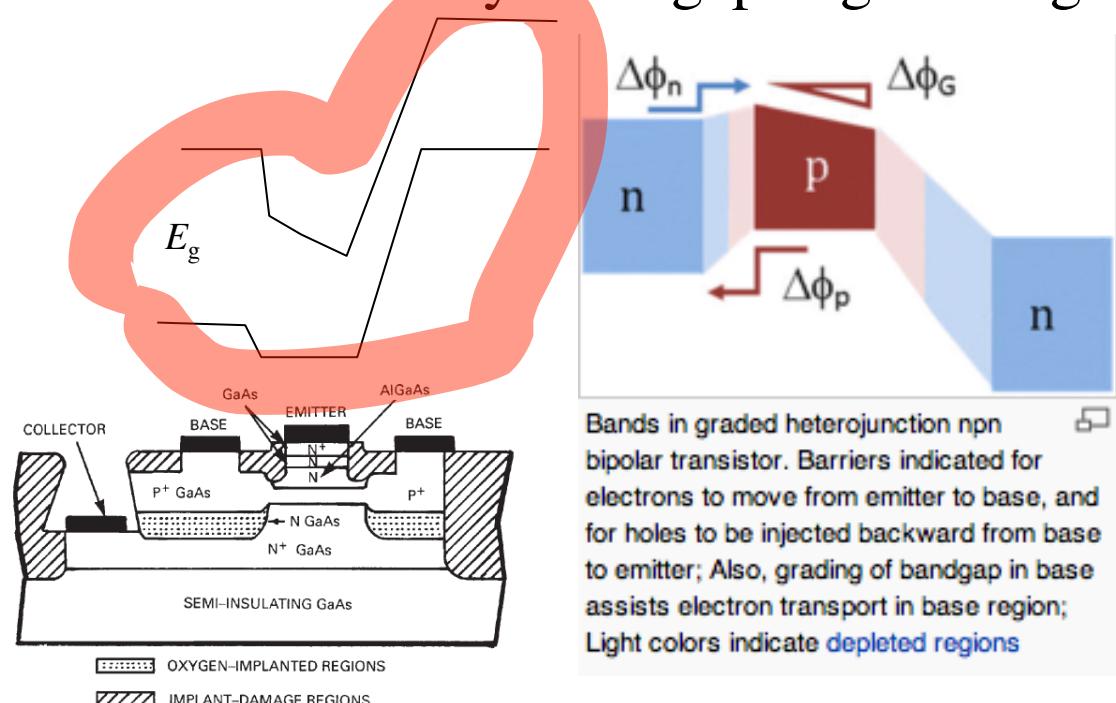
Also maximize speed

Graded base by doping



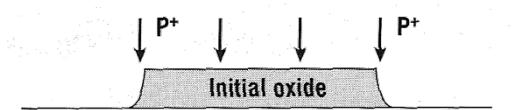
Gives electrical field in base

Graded base by band gap engineering

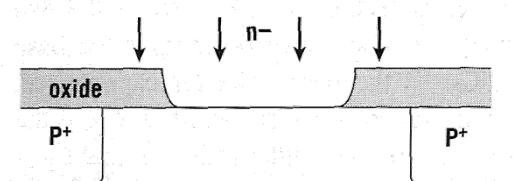


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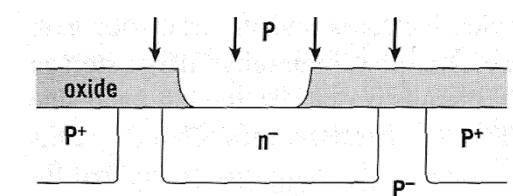
Bipolar Process Integration



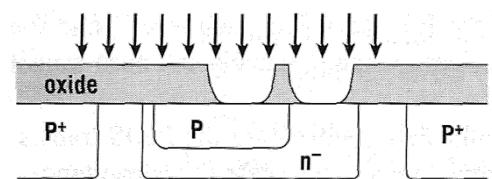
(1) Initial oxidation and guard ring implantation



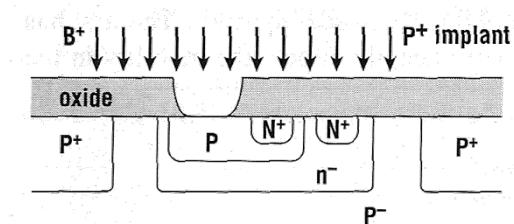
(2) Guard ring drive, collector oxidation, collector implant



(3) Collector drive, base oxidation, base implant



(4) Base drive, emitter oxidation, emitter implant



(5) Base contact oxidation, base contact implant

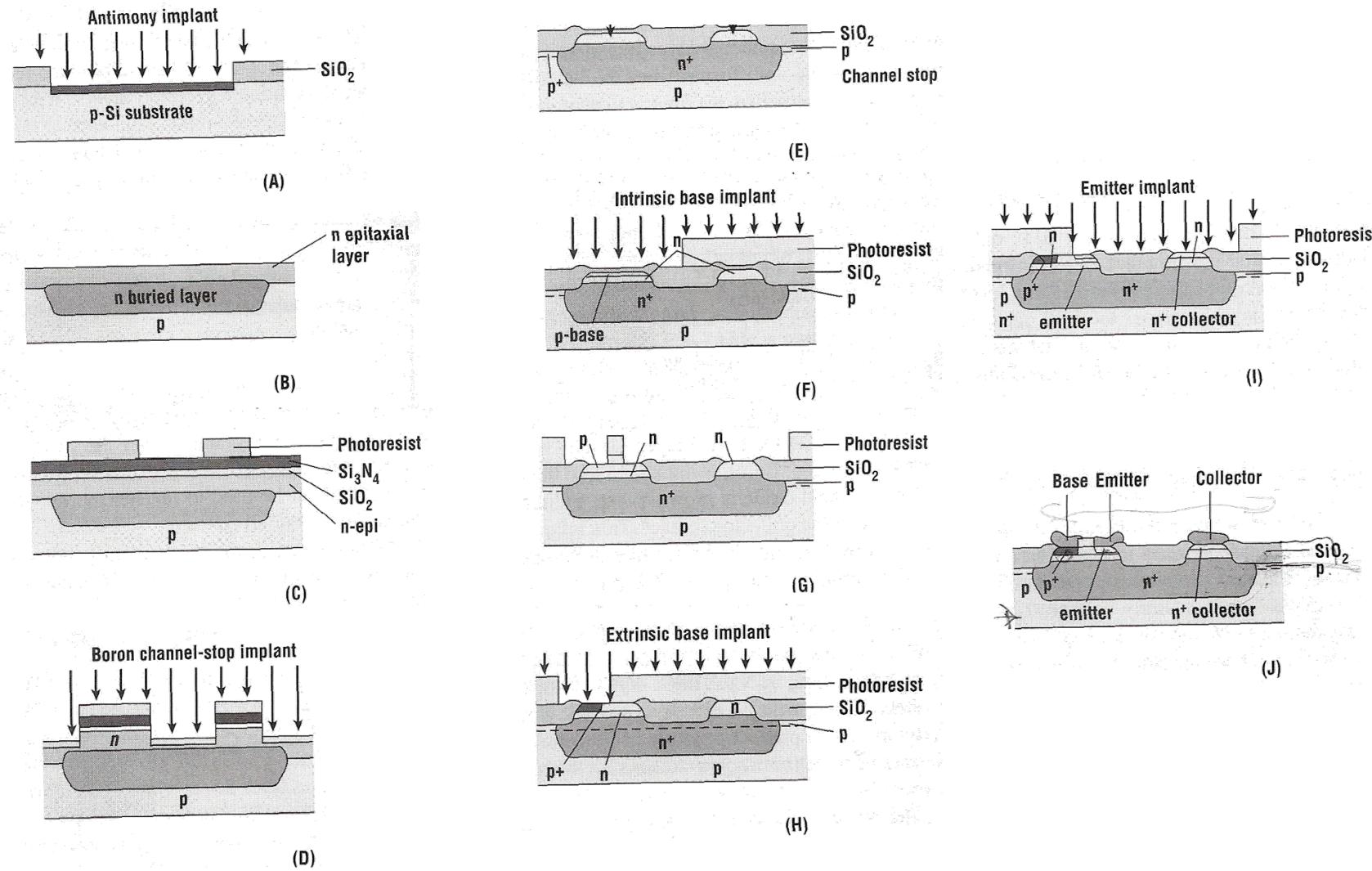
Figure 17.17 Process flow for a simple junction isolated triple diffused bipolar technology.

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Bipolar Process Integration

Oxide isolated triple diffused bipolar

Figure 17.19 Process flow for an oxide isolated triple-diffused bipolar technology without sinkers.
 Steps i
 A) buried layer formation, (B) epitaxial growth, (C) LOCOS patterning, (D) silicon
 recessing and channel stop implants, (E) local oxidation, (F) intrinsic base implant, (G) contact mask,
 (H) extrinsic base implant, (I) emitter and collector contact implant, and (J) metallization (after Sze,
 reprinted by permission of John Wiley & Sons).

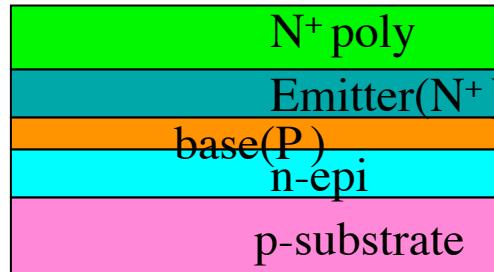
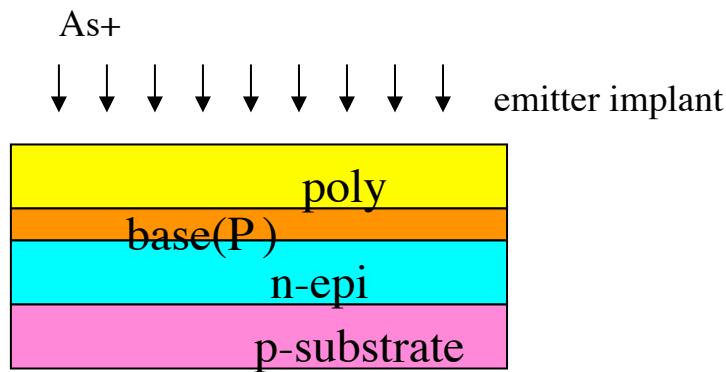
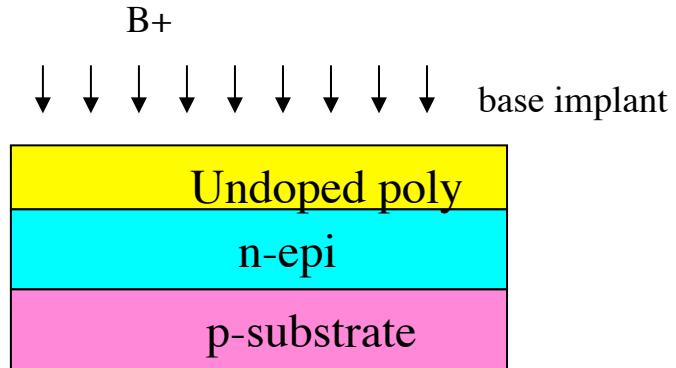


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Bipolar Process Integration

PolySi as diffusion source
For shallow junctions

Implant in Poly



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Bipolar Process Integration

Self –aligned doubly-poly bipolar

Reduces base-collector capacitance
Also much reduced footprint

The emitter stripe width is less than the minimum lithographic feature width,
typical it is $0.3 \mu\text{m}$ for $0.5 \mu\text{m}$ lithography

LOCOS oxide isolated

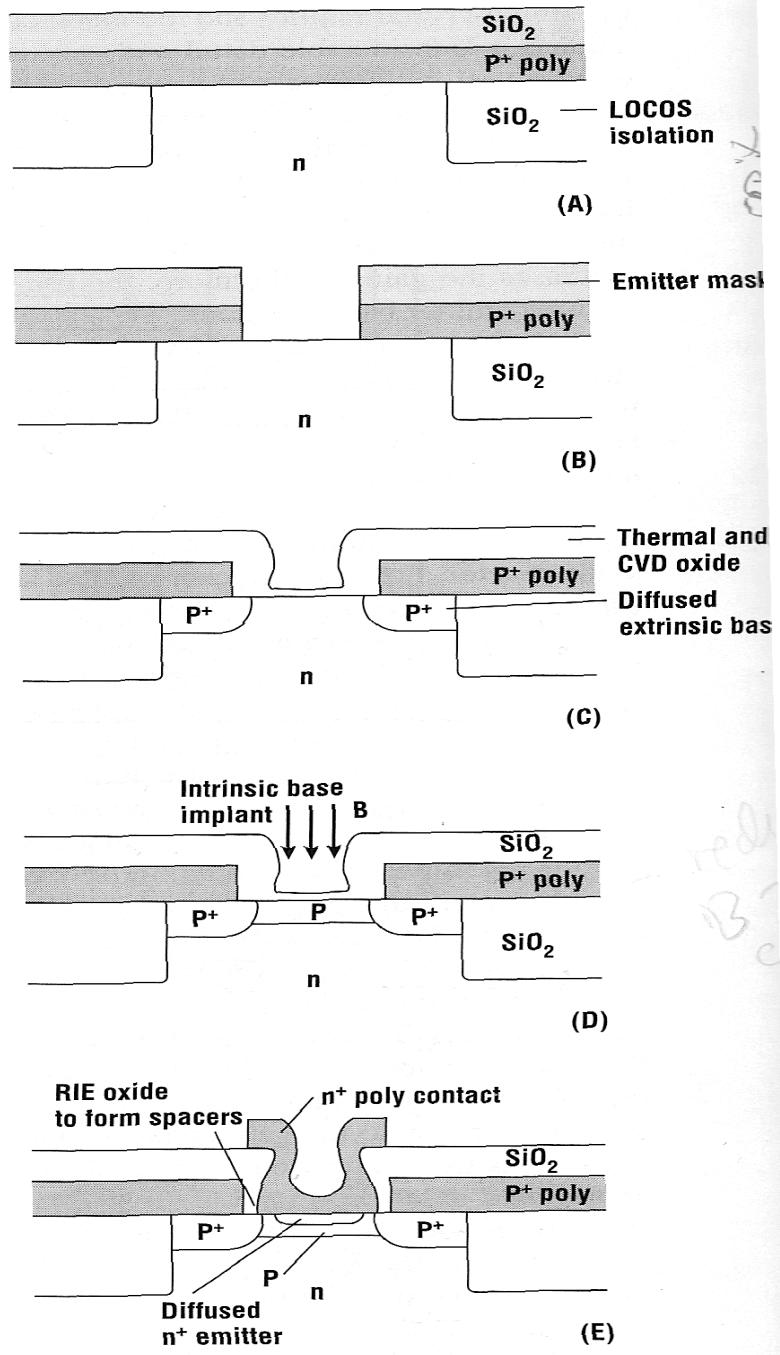


Figure 18.11 Simple process flow for a self-aligned doubly-poly bipolar technology.

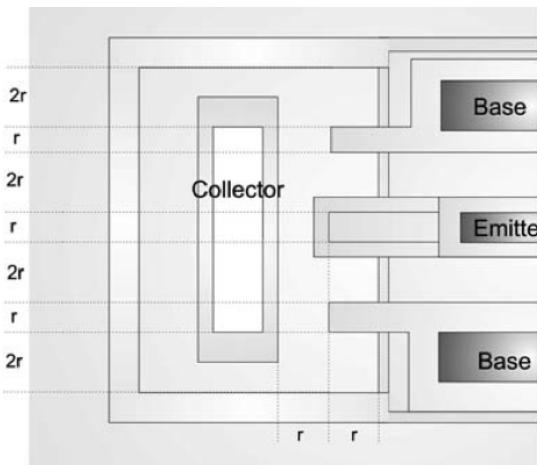
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Bipolar Process Integration

SOI LBJT Lateral BJT

Reduces substrate capacitance
Oscillation freq 128 GHz

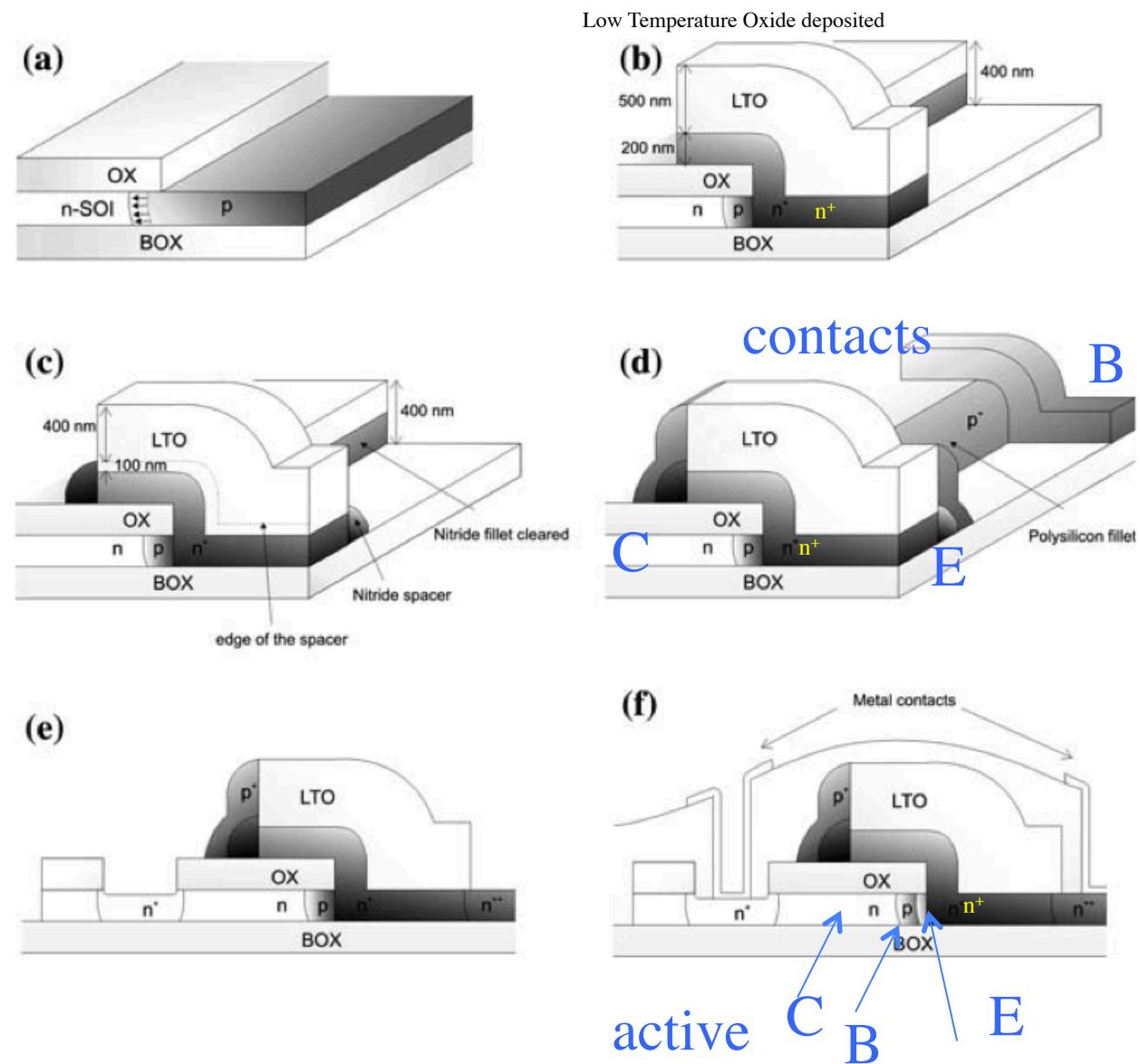
Transistor dimensions down to
 $(0.2\text{--}0.5) \cdot (0.13\text{--}0.25) \mu\text{m}^2$



Self –aligned doubly-poly lateral bipolar

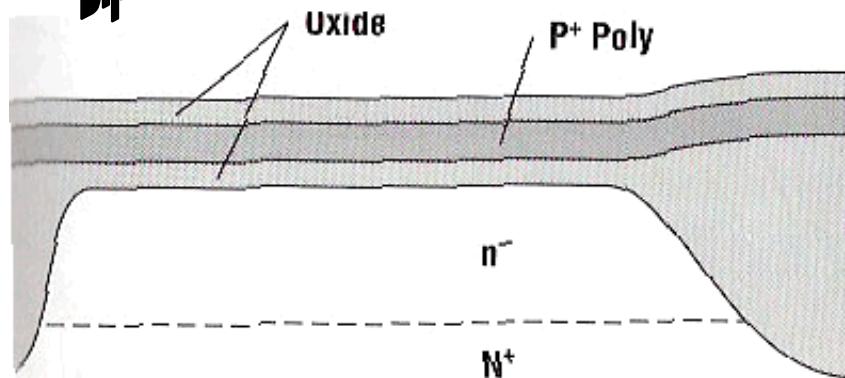
P. Pengpad · D. M. Bagnall

J Mater Sci: Mater Electron (2008) 19:183–187
DOI 10.1007/s10854-007-9300-y

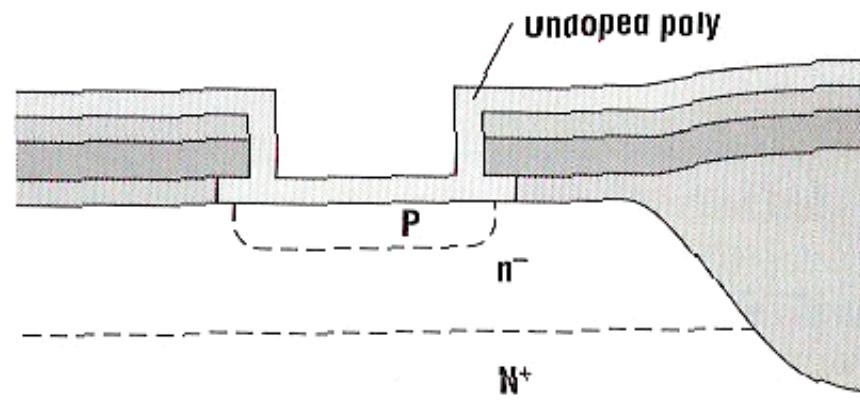


FYS450
Bipolar Process Integration

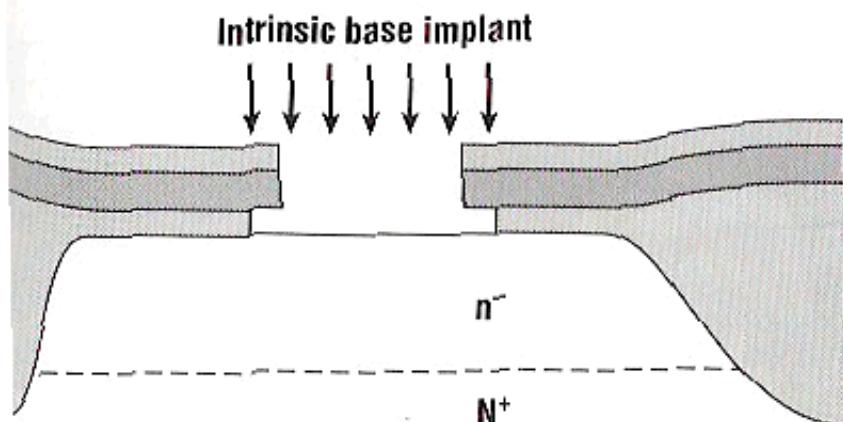
“Antipov” emitter bipolar



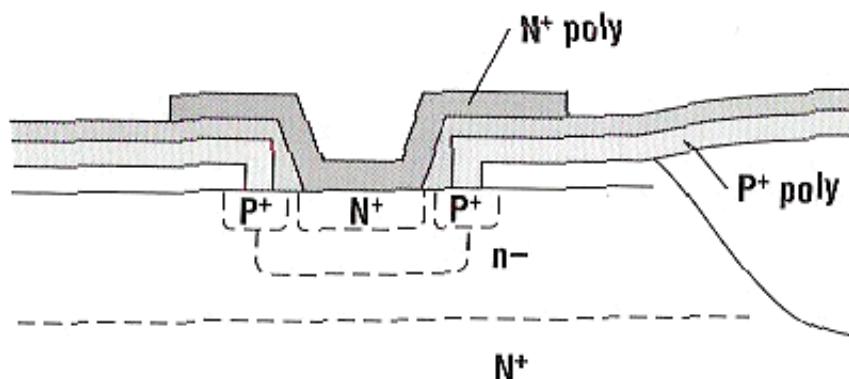
(A)



(C)



(B)



(D)

LOCOS oxide isolated

Figure 18.14 The super self-aligned or Antipov emitter bipolar transistor.

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Bipolar Process Integration

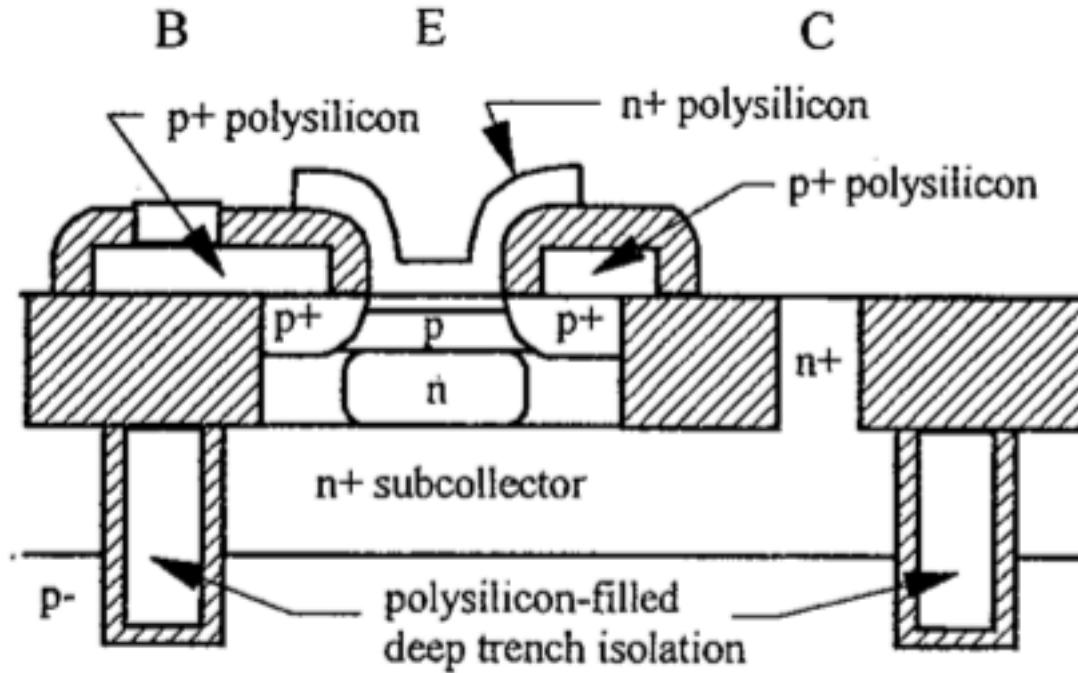
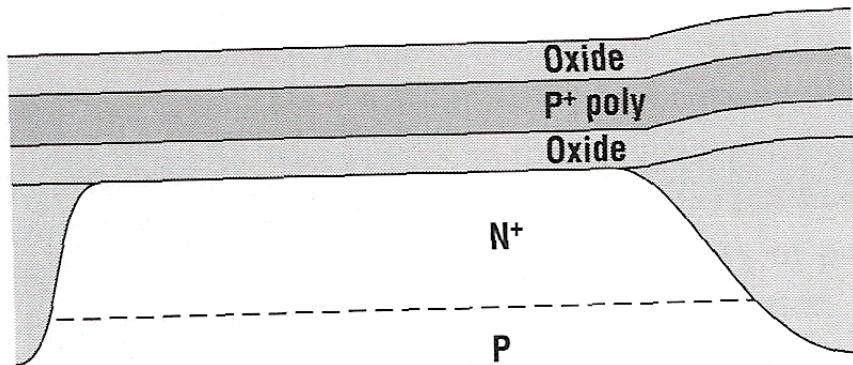


Fig. 1. Schematic cross-sectional view of a trench-isolated double-polysilicon self-aligned bipolar transistor with a pedestal collector (advanced bipolar transistor).

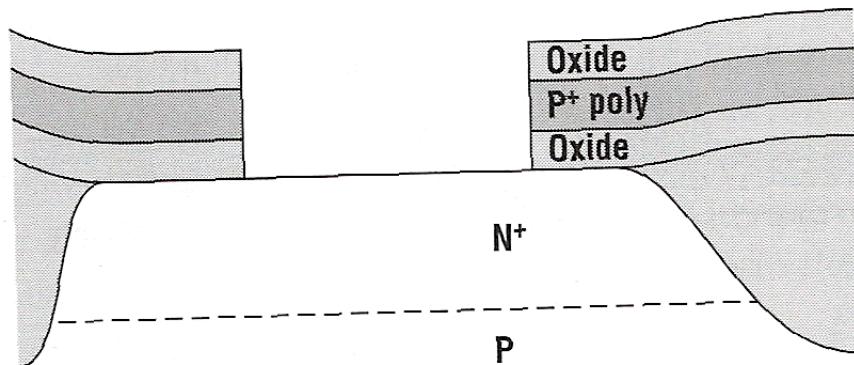
Trench isolated

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Bipolar Process Integration

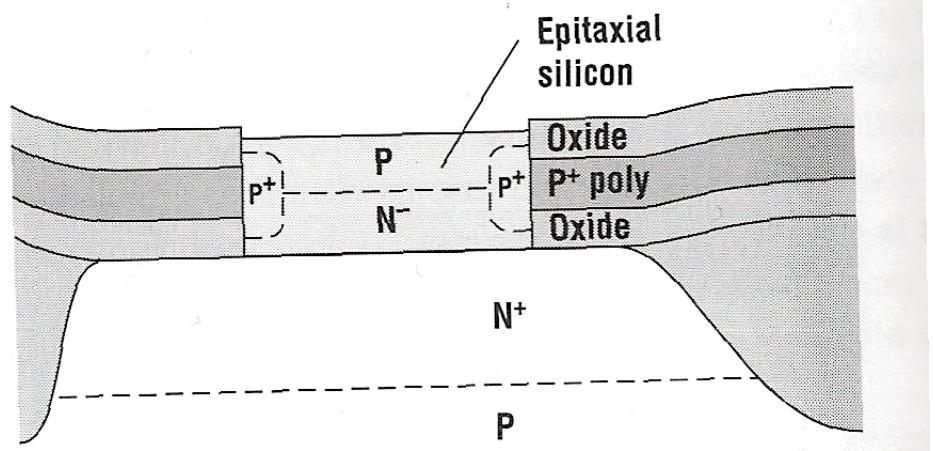


(A)

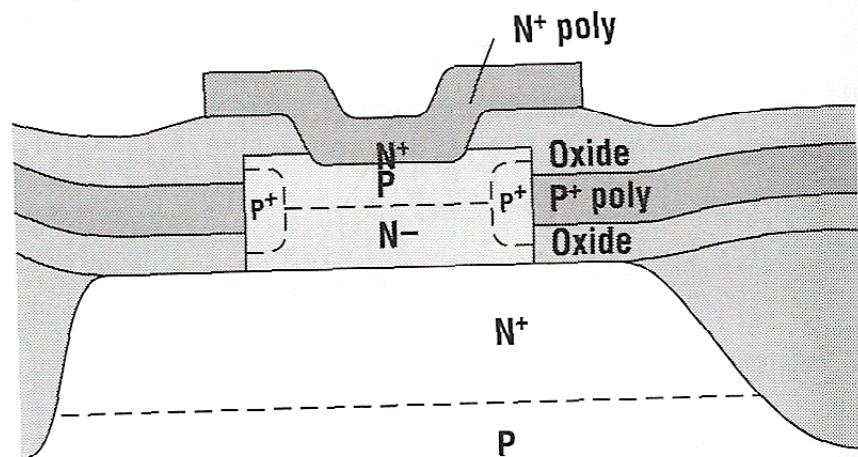


(B)

LOCOS oxide isolated



(C)

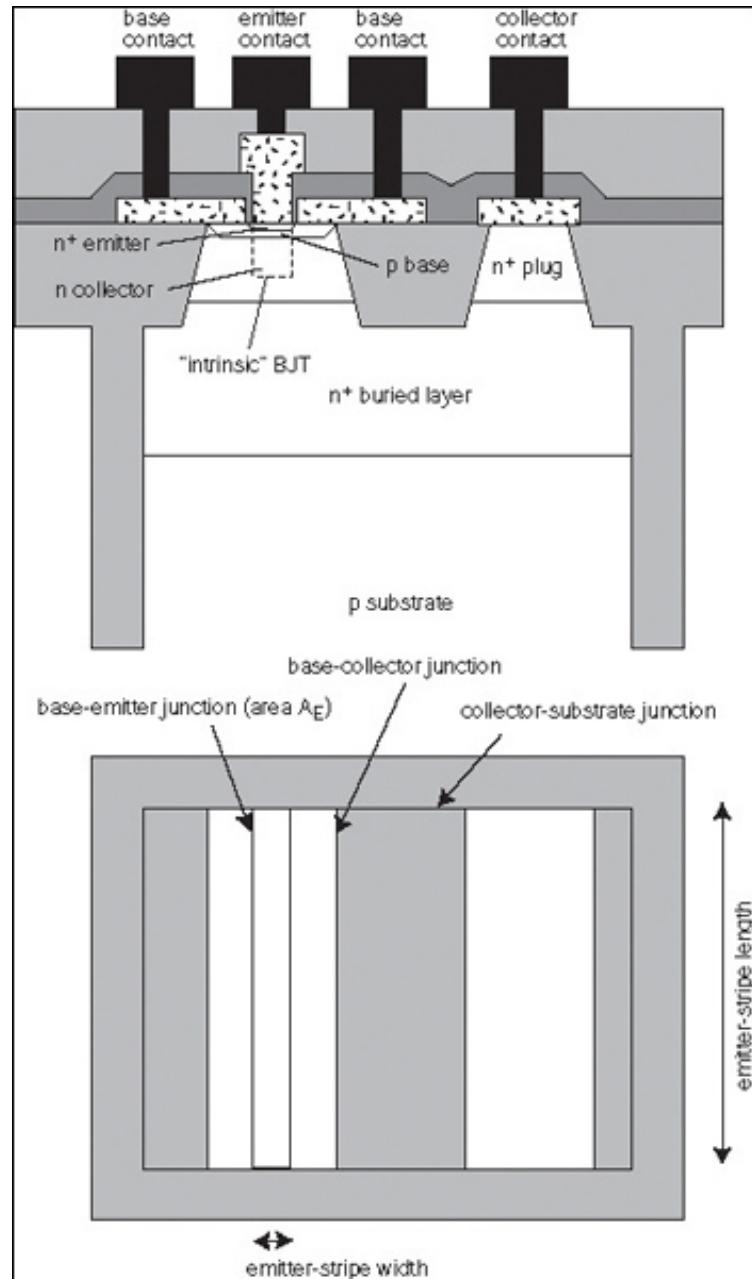


(D)

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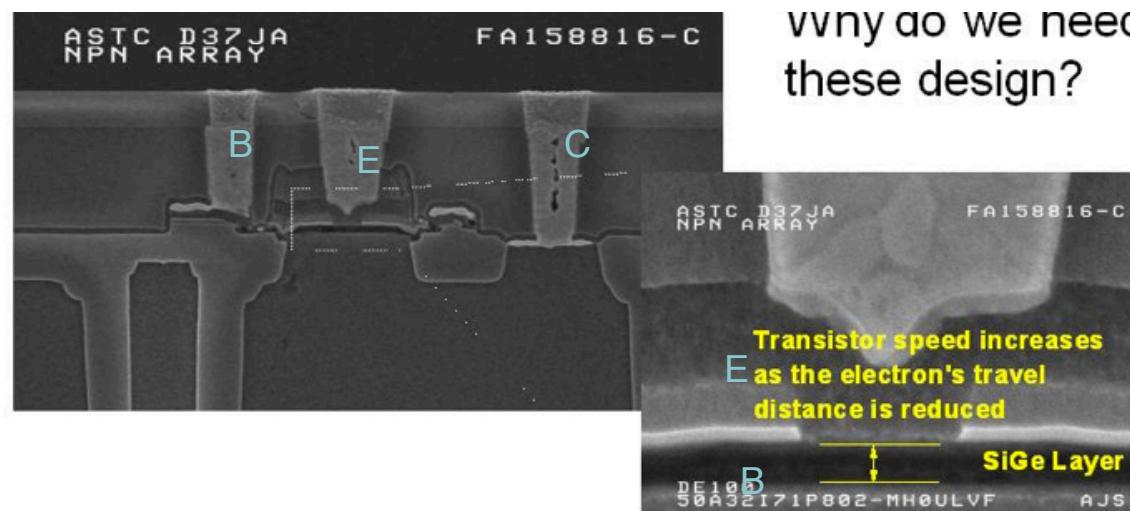
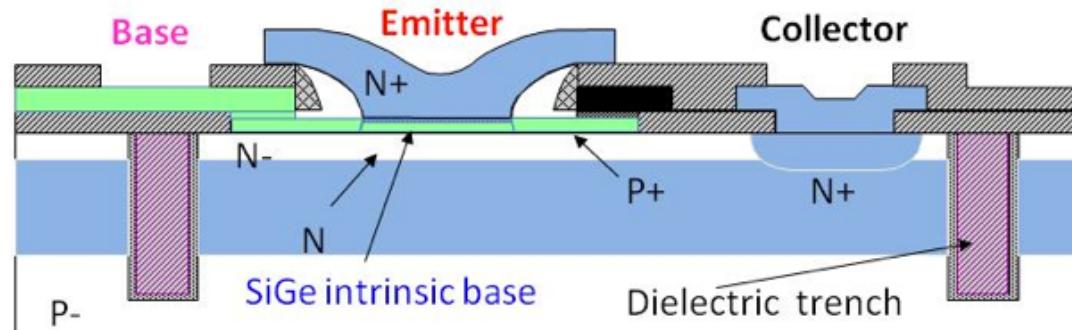
Bipolar Process Integration

Trench isolated



FYS4510 Bipolar Process Integration

Trench isolated SiGe



vvny do we need all these design?

FYS 530
Bipolar Process Integration

PRETTY? PICTURE

Amazing!

SiGe

